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Pages 1 to 30

**INTEGRATED CIRCUITS, SILICON MONOLITHIC,  
BIPOlar, ADVANCED LOW POWER SCHOTTKY,  
DUAL, J-K̄ POSITIVE-EDGE-TRIGGERED  
FLIP-FLOPS WITH CLEAR AND PRESET,  
BASED ON TYPES 54ALS109 AND 54ALS109A  
ESA/SCC Detail Specification No. 9203/049**



**space components  
coordination group**

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		SCCG Chairman	ESA Director General or his Deputy
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**SCC**ESA/SCC Detail Specification  
No. 9203/049

Rev. 'A'

PAGE 2

ISSUE 2

**DOCUMENTATION CHANGE NOTICE**

Rev. Letter	Rev. Date	Reference	CHANGE Item	Approved DCR No.
		This Issue supersedes Issue 1 and incorporates all modifications defined in Revisions 'A' and 'B' to Issue 1 and the following DCR's:-		
		Cover Page		None
		DCN		None
		Table 1(a)	: Lead Material and/or Finish amended	22881
		Figure 2	: Imperial dimensions and references deleted	22881
		Figure 2(c)	: In drawing, Note 6 corrected to "10"	23456
		Notes to Figures	: Title amended	22881
			: Note 1, amended to read "...Figure 2(b)"	22881
		Figure 3(a)	: Comparison Table added	22881
		Para. 4.2.2	: Deviation deleted, "None." added	21048
		Para. 4.2.4	: Deviation deleted, "None" added	22919
		Para. 4.2.5	: Deviation deleted, "None" added	22919
		Para. 4.4.2	: Paragraph amended	22881
		Para. 4.5.2	: Amended to read "...Figure 2(b)"	22881
		Para. 4.5.3	: "Type Variant, as applicable" amended to refer to Table 1(a)	23455
		Para. 4.6.3	: Reference to functional test sequence deleted	23455
		Para. 4.7.1	: Expanded to identify the stated temperature as $T_{amb}$	23455
		Figure 4(f)	: Note 1, "shorted" amended to read "tested"	23455
		Figure 5	; In drawing "And 54ALS109A" added	23456
		Para. 4.8	: Title expanded	23455
'A'	Feb.'94	Cover Page		None
		DCN		None
		P15. Para. 4.3.2	: Weights amended	221047
		P19. Table 2ac	: Numbering and applicable pins amended	23586

**TABLE OF CONTENTS**

	<u>Page</u>
<b>1. <u>GENERAL</u></b>	<b>5</b>
1.1 Scope	5
1.2 Component Type Variants	5
1.3 Maximum Ratings	5
1.4 Parameter Derating Information	5
1.5 Physical Dimensions	5
1.6 Pin Assignment	5
1.7 Truth Table	5
1.8 Circuit Schematic	5
1.9 Functional Diagram	5
<b>2. <u>APPLICABLE DOCUMENTS</u></b>	<b>14</b>
<b>3. <u>TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS</u></b>	<b>14</b>
<b>4. <u>REQUIREMENTS</u></b>	<b>14</b>
4.1 General	14
4.2 Deviations from Generic Specification	14
4.2.1 Deviations from Special In-process Controls	14
4.2.2 Deviations from Final Production Tests	14
4.2.3 Deviations from Burn-in Tests	14
4.2.4 Deviations from Qualification Tests	14
4.2.5 Deviations from Lot Acceptance Tests	15
4.3 Mechanical Requirements	15
4.3.1 Dimension Check	15
4.3.2 Weight	15
4.4 Materials and Finishes	15
4.4.1 Case	15
4.4.2 Lead Material and Finish	15
4.5 Marking	15
4.5.1 General	15
4.5.2 Lead Identification	15
4.5.3 The SCC Component Number	16
4.5.4 Traceability Information	16
4.6 Electrical Measurements	16
4.6.1 Electrical Measurements at Room Temperature	16
4.6.2 Electrical Measurements at High and Low Temperatures	16
4.6.3 Circuits for Electrical Measurements	16
4.7 Burn-in Tests	16
4.7.1 Parameter Drift Values	16
4.7.2 Conditions for Power Burn-in	16
4.7.3 Electrical Circuits for Power Burn-in	16
4.8 Environmental and Endurance Tests	28
4.8.1 Electrical Measurements on Completion of Environmental Tests	28
4.8.2 Electrical Measurements at Intermediate Points during Endurance Tests	28
4.8.3 Electrical Measurements on Completion of Endurance Tests	28
4.8.4 Conditions for Operating Life Tests	28
4.8.5 Electrical Circuits for Operating Life Tests	28
4.8.6 Conditions for High Temperature Storage Test	28

**TABLES**

	<u>Page</u>
1(a) Type Variants	6
1(b) Maximum Ratings	6
2 Electrical Measurements at Room Temperature, d.c. Parameters	17
Electrical Measurements at Room Temperature, a.c. Parameters	19
3 Electrical Measurements at High and Low Temperatures	21
4 Parameter Drift Values	26
5 Conditions for Power Burn-in and Operating Life Test	26
6 Electrical Measurements on Completion of Environmental Tests and at Intermediate Points and on Completion of Endurance Tests	29

**FIGURES**

1 Not applicable	
2 Physical Dimensions	7
3(a) Pin Assignment	11
3(b) Truth Table	12
3(c) Circuit Schematic	13
3(d) Functional Diagram	13
4 Circuits for Electrical Measurements	23
5 Electrical Circuit for Power Burn-in and Operating Life Test	27

**APPENDICES (Applicable to specific Manufacturers only)**

'A' Agreed Deviations for Texas Instruments (F)	30
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**1. GENERAL****1.1 SCOPE**

This specification details the ratings, physical and electrical characteristics, test and inspection data for a silicon monolithic, bipolar, advanced low power Schottky, Dual, J-K Positive-Edge-Triggered Flip-Flop with clear and preset, based on Types 54ALS109 and 54ALS109A. It shall be read in conjunction with ESA/SCC Generic Specification No. 9000, the requirements of which are supplemented herein.

**1.2 COMPONENT TYPE VARIANTS**

Variants of the basic type integrated circuits specified herein, which are also covered by this specification, are given in Table 1(a).

**1.3 MAXIMUM RATINGS**

The maximum ratings, which shall not be exceeded at any time during use or storage, applicable to the integrated circuits specified herein, are as scheduled in Table 1(b).

**1.4 PARAMETER DERATING INFORMATION (FIGURE 1)**

Not applicable.

**1.5 PHYSICAL DIMENSIONS**

The physical dimensions of the integrated circuits specified herein are shown in Figure 2.

**1.6 PIN ASSIGNMENT**

As per Figure 3(a).

**1.7 TRUTH TABLE**

As per Figure 3(b).

**1.8 CIRCUIT SCHEMATIC**

As per Figure 3(c).

**1.9 FUNCTIONAL DIAGRAM**

As per Figure 3(d).



**TABLE 1(a) - TYPE VARIANTS**

VARIANT	BASED ON TYPE	CASE	FIGURE	LEAD MATERIAL AND/OR FINISH
01	54ALS109	FLAT	2(a)	D7
02	54ALS109	FLAT	2(a)	G4
03	54ALS109	CCP	2(b)	7
04	54ALS109	CCP	2(b)	4
05	54ALS109	DIL	2(c)	D7
06	54ALS109	DIL	2(c)	G4
07	54ALS109A	FLAT	2(a)	D7
08	54ALS109A	FLAT	2(a)	G4
09	54ALS109A	CCP	2(b)	7
10	54ALS109A	CCP	2(b)	4
11	54ALS109A	DIL	2(c)	D7
12	54ALS109A	DIL	2(c)	G4

**TABLE 1(b) - MAXIMUM RATINGS**

NO.	CHARACTERISTICS	SYMBOL	MAXIMUM RATINGS	UNIT	REMARKS
1	Supply Voltage	$V_{CC}$	-0.5 to 7.0	V	-
2	Input Voltage	$V_{IN}$	-0.5 to 7.0	V	Note 1
3	Device Dissipation	$P_D$	22	mWdc	Note 2
4	Operating Temperature Range	$T_{op}$	-55 to +125	°C	-
5	Storage Temperature Range	$T_{stg}$	-65 to +150	°C	-
6	Soldering Temperature For FP and DIP For CCP	$T_{sol}$	+265 +245	°C	Note 3 Note 4

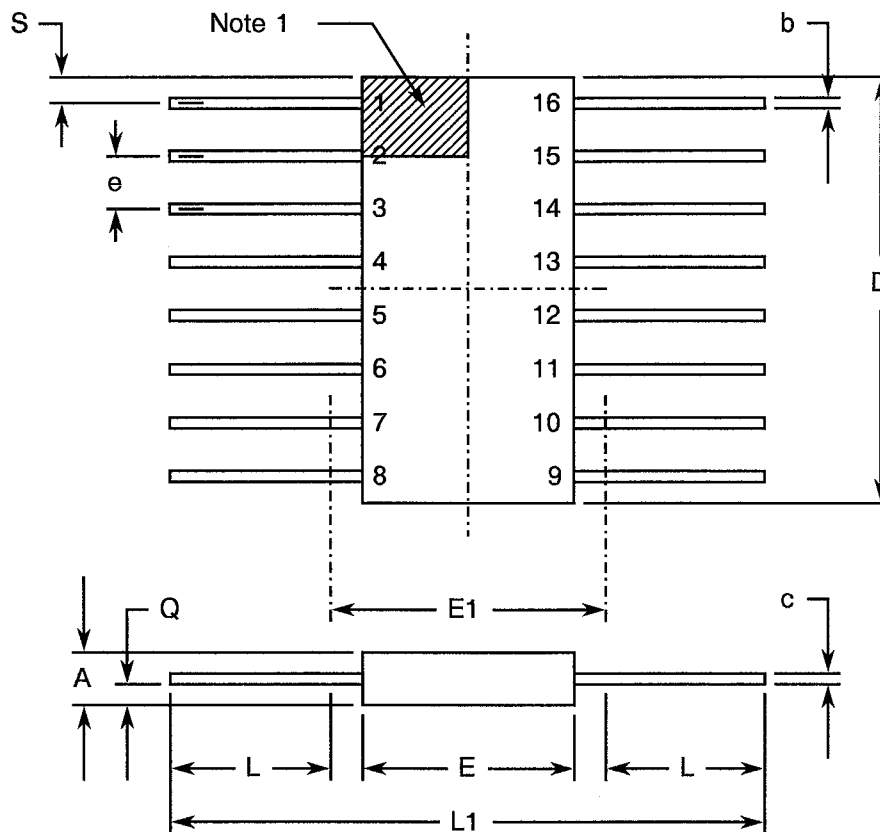
**NOTES**

1. Input Current limited to -18mA.
2. Must withstand added  $P_D$  due to short circuit conditions (i.e.  $I_{OS}$ ) at 1 output for 5 seconds.
3. Duration 10 seconds maximum at a distance of not less than 1.5mm from the package and the same lead shall not be resoldered until 3 minutes have elapsed.
4. Duration 5 seconds maximum and the same terminal shall not be resoldered until 3 minutes have elapsed.



**FIGURE 2 - PHYSICAL DIMENSIONS**

**FIGURE 2(a) - FLAT PACKAGE**



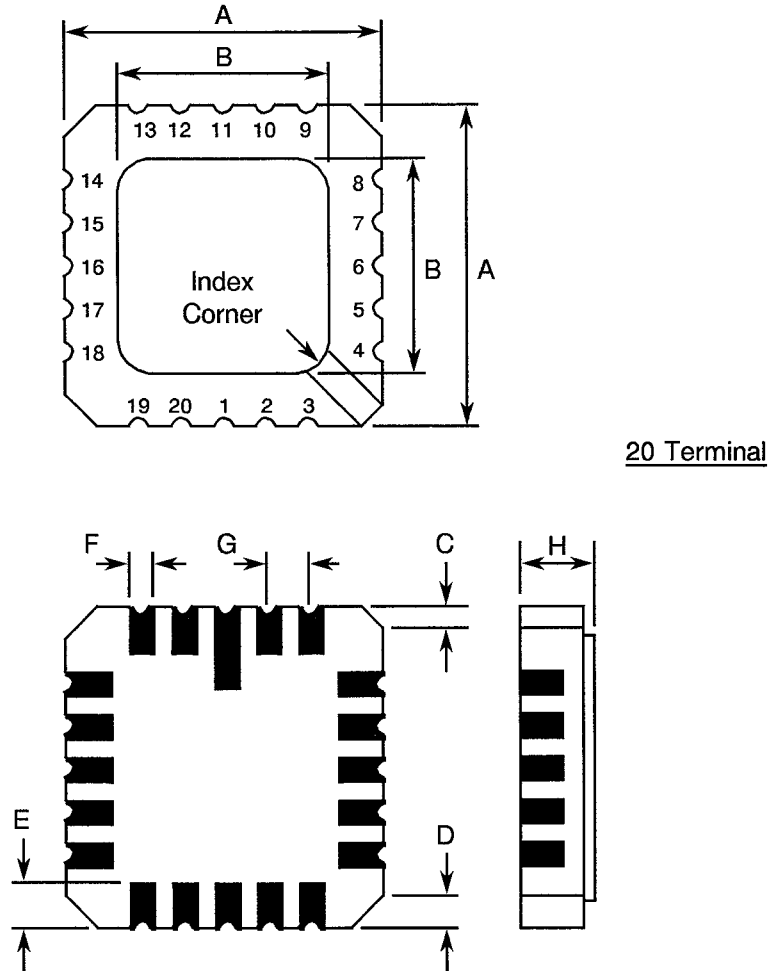
SYMBOL	MILLIMETRES		NOTES
	MIN	MAX	
A	1.24	2.03	
b	0.38	0.48	8
c	0.08	0.15	8
D	9.65	11.02	
E	6.10	6.60	
E1	-	7.11	4
e	1.27 TYPICAL		5, 9
L	6.35	9.40	
L1	19.05	-	
Q	0.25	0.89	2
S	0.25	0.76	7

**NOTES:** See Page 10.



**FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)**

**FIGURE 2(b) - SQUARE CHIP CARRIER PACKAGE (3 LAYER BASE)**



SYMBOL	MILLIMETRES		NOTES
	MIN	MAX	
A	8.687	9.093	
B	7.798	9.093	
C	0.250	0.510	11
D	0.889	1.143	12
E	1.140	1.400	8
F	0.559	0.712	8
G	1.27 TYPICAL		5, 9
H	1.630	2.540	

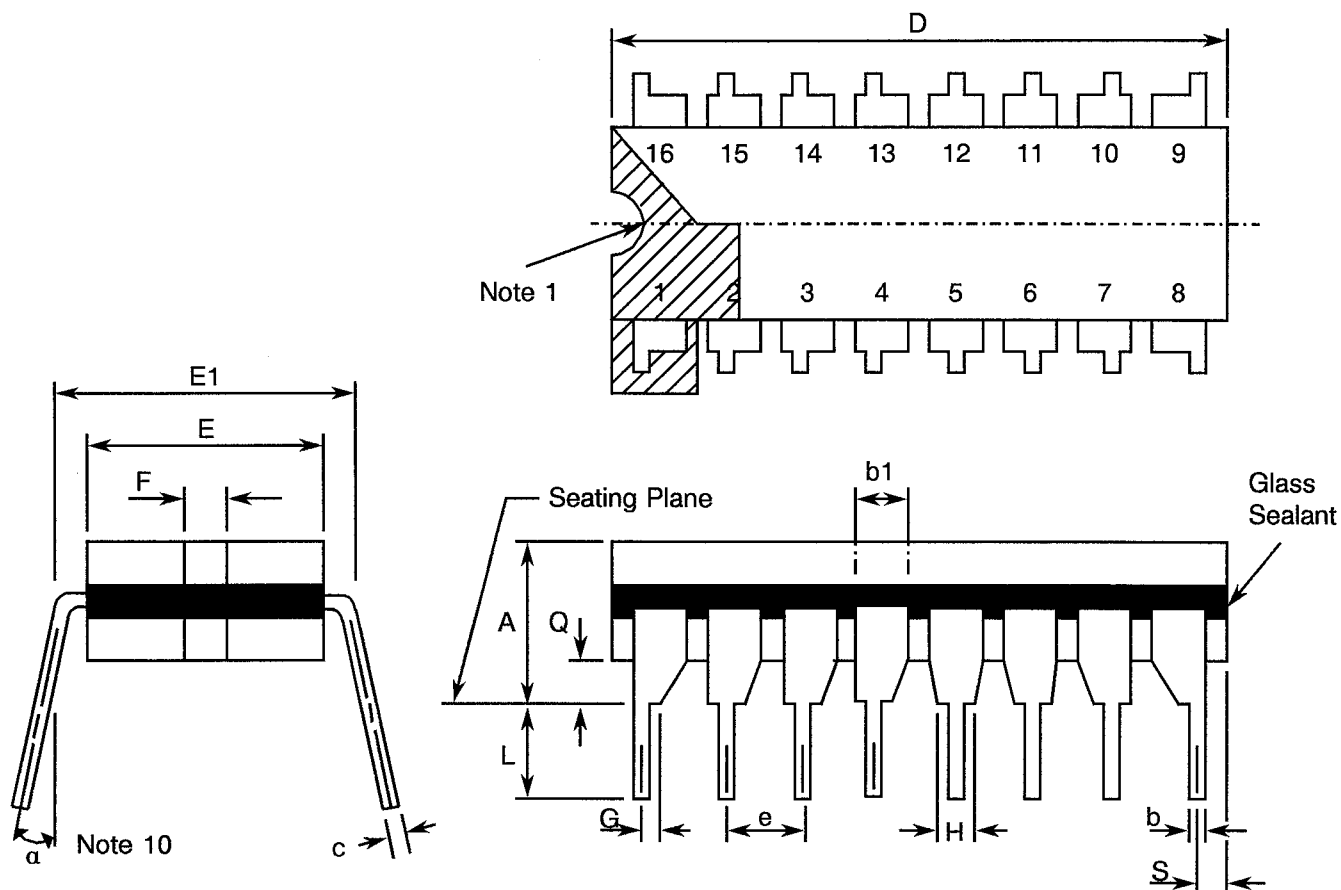
**NOTES:** See Page 10.





**FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)**

**FIGURE 2(c) - DUAL-IN-LINE PACKAGE**



SYMBOL	MILLIMETRES		NOTES
	MIN	MAX	
A	-	5.08	
b	0.38	0.58	8
b1	-	1.78	8
c	0.203	0.356	8
D	19.18	19.94	
E	6.22	7.11	
E1	7.37	7.87	4
e	2.54 TYPICAL		6, 9
G	0.305	-	13
H	0.76	-	14
L	3.30	5.08	
Q	0.51	2.03	3
S	0.38	1.27	7
a	0°	15°	10

**NOTES:** See Page 10.

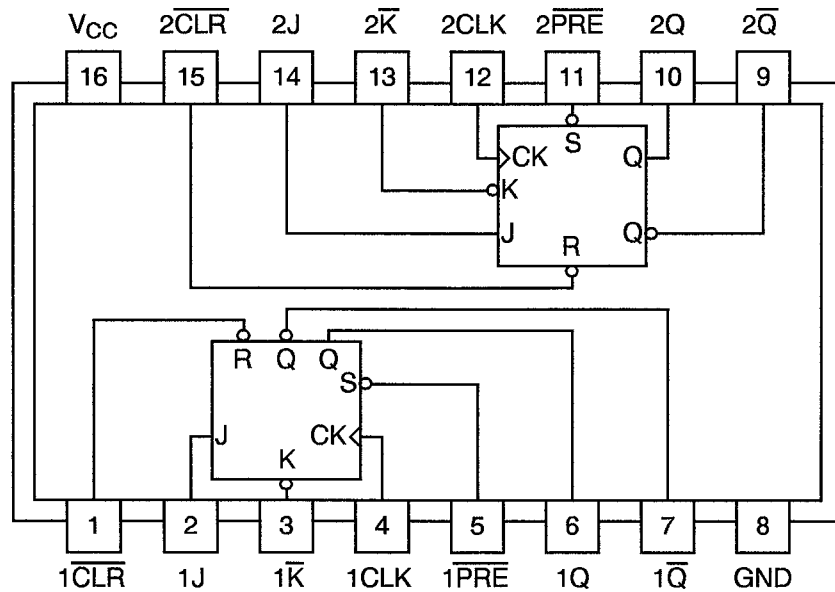
**FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)****NOTES TO FIGURES 2(a) TO 2(c) INCLUSIVE**

1. Index area; a notch or dot shall be located adjacent to Pin 1 and shall be within the shaded area shown. For chip carrier packages the index shall be as defined in Figure 2(b).
2. Dimension Q shall be measured at the point of exit of the lead from the body.
3. Dimension Q shall be measured from the seating plane to the base plane.
4. This dimension allows for off-centre lids, meniscus and glass overrun.
5. The true position pin or terminal spacing is 1.27mm between centrelines. Each pin or terminal centreline shall be located within  $\pm 0.13\text{mm}$  of its true longitudinal position relative to Pins 1 and the highest pin number.
6. The true position pin spacing is 2.54mm between centrelines. Each pin centreline shall be located within  $\pm 0.25\text{mm}$  of its true longitudinal position relative to Pins 1 and the highest pin number.
7. Applies to all 4 corners.
8. All leads or terminals.
9. 14 spaces for flat and dual-in-line packages.  
16 spaces for chip carrier packages.
10. Lead centre when  $\alpha$  is  $0^\circ$ .
11. Index corner only - 2 dimensions.
12. 3 non-index corners - 6 dimensions.
13. 4 Terminals.
14. 12 Terminals.



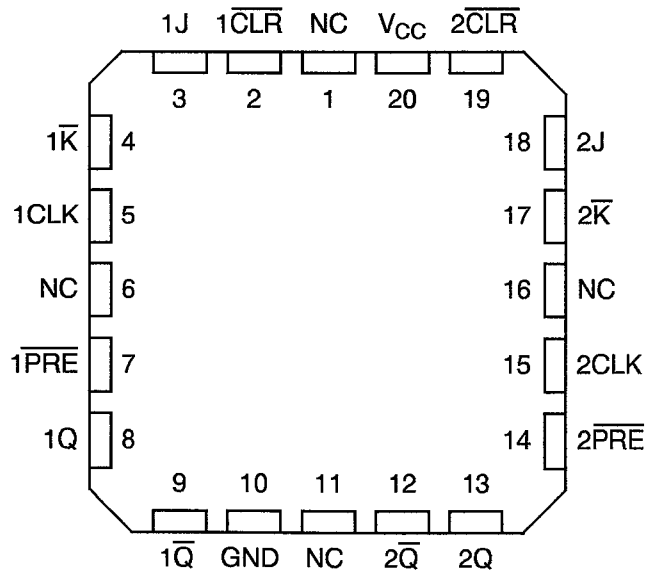
**FIGURE 3(a) - PIN ASSIGNMENT**

DUAL-IN-LINE AND FLAT PACKAGE



TOP VIEW

CHIP CARRIER PACKAGE



TOP VIEW

FLAT PACKAGE AND DUAL-IN-LINE TO CHIP CARRIER PIN ASSIGNMENT

FLAT PACKAGE AND DUAL-IN-LINE PIN OUTS	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
CHIP CARRIER PIN OUTS	2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20

**FIGURE 3(b) - TRUTH TABLE**FUNCTION TABLE (EACH FLIP-FLOP)

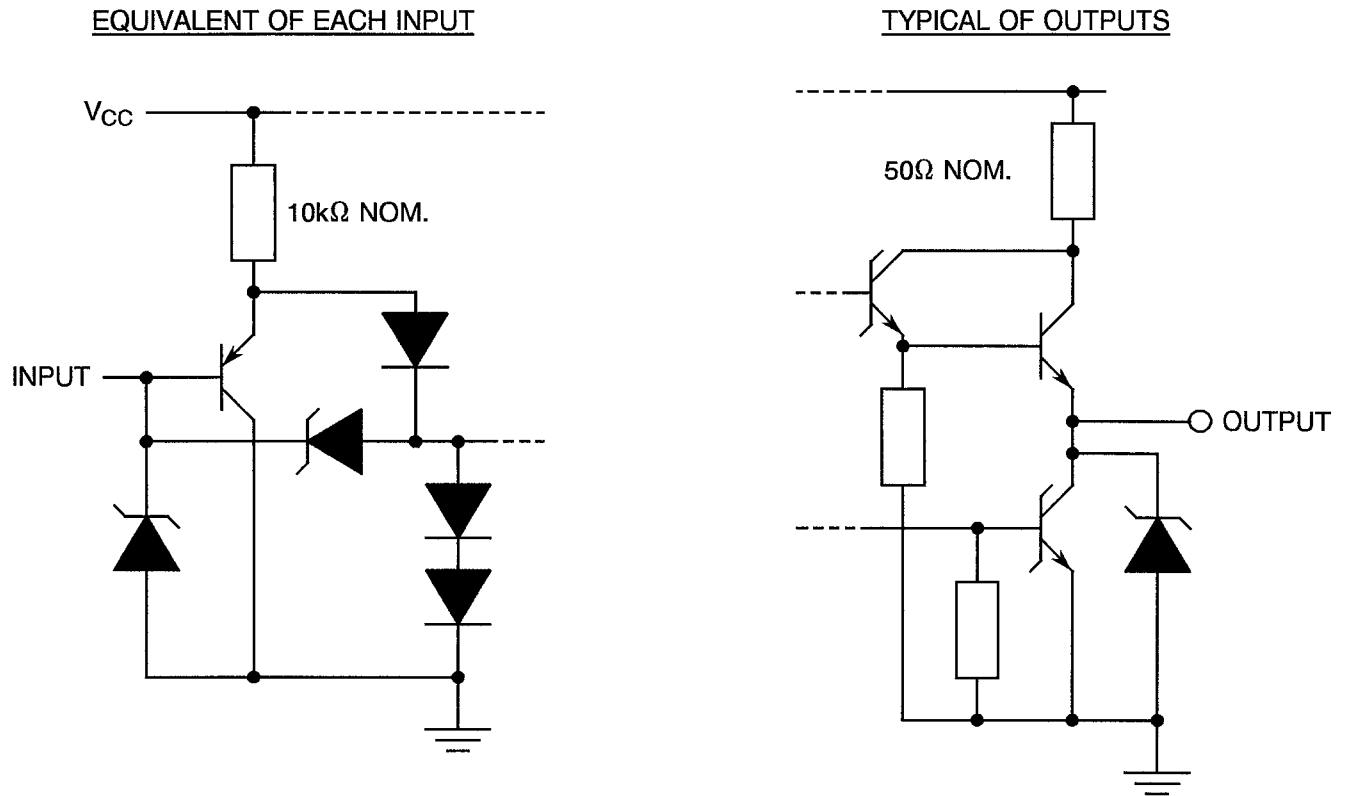
INPUTS					OUTPUTS	
$\overline{\text{PRESET}}$	$\overline{\text{CLEAR}}$	CLOCK	J	$\overline{K}$	Q	$\overline{Q}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H (4)	H (4)
H	H	↑	L	L	L	H
H	H	↑	H	L	TOGGLE	
H	H	↑	L	H	$Q_0$	$\overline{Q}_0$
H	H	↑	H	H	H	L
H	H	L	X	X	$Q_0$	$\overline{Q}_0$

**NOTES**

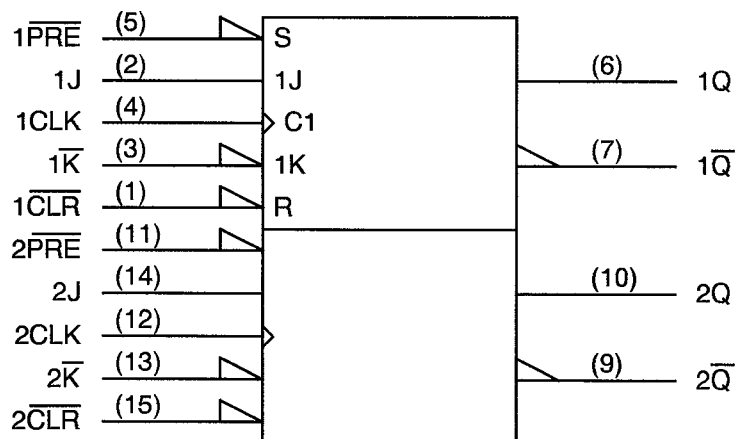
1. H = High Level (Steady State), L = Low Level (Steady State), X = Irrelevant.
2.  $Q_0$  and  $\overline{Q}_0$  = Level of Q and  $\overline{Q}$  before indicated steady-state input conditions were established.
3. ↑ = Transition from Low to High Level.
4. The output levels in this configuration are not guaranteed to meet the minimum levels for  $V_{OH}$  if the lows at  $\overline{\text{PRESET}}$  and  $\overline{\text{CLEAR}}$  are near  $V_{IL}$  maximum. This configuration is nonstable and will not persist when  $\overline{\text{PRESET}}$  or  $\overline{\text{CLEAR}}$  return to their inactive (high) level.



**FIGURE 3(c) - CIRCUIT SCHEMATIC**



**FIGURE 3(d) - FUNCTIONAL DIAGRAM**



**NOTES**

1. Pin numbers shown are for flat and dual-in-line packages; for chip carrier pins, see Figure 3(a).

**2. APPLICABLE DOCUMENTS**

The following documents form part of this specification and shall be read in conjunction with it:-

- (a) ESA/SCC Generic Specification No. 9000 for Integrated Circuits.
- (b) MIL-STD-883, Test Methods and Procedures for Micro-electronics.

**3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS**

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply. In addition, the following abbreviation is used:-

$I_{OS/2}$  - One half of the true output short circuit current.

**4. REQUIREMENTS****4.1 GENERAL**

The complete requirements for procurement of the integrated circuits specified herein shall be as stated in this specification and ESA/SCC Generic Specification No. 9000 for Integrated Circuits. Deviations from the Generic Specification, applicable to this specification only, are listed in Para. 4.2.

Deviations from the applicable Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESA/SCC requirements and do not affect the components' reliability, are listed in the appendices attached to this specification.

**4.2 DEVIATIONS FROM GENERIC SPECIFICATION****4.2.1 Deviations from Special In-process Controls**

None.

**4.2.2 Deviations from Final Production Tests (Chart II)**

None.

**4.2.3 Deviations from Burn-in Tests (Chart III)**

- (a) Para. 7.1.1(a), "High Temperature Reverse Bias" tests and subsequent electrical measurements related to this test shall be omitted.
- (b) Para. 9.9.2, "Electrical Measurements at High and Low Temperatures": Only a test result summary, based on go-no-go tests and presented in histogram form is required.

**4.2.4 Deviations from Qualification Tests (Chart IV)**

None.



#### 4.2.5 Deviations from Lot Acceptance Tests (Chart V)

None.

### 4.3 MECHANICAL REQUIREMENTS

#### 4.3.1 Dimension Check

The dimensions of the integrated circuits specified herein shall be checked. They shall conform to those shown in Figure 2.

#### 4.3.2 Weight

The maximum weight of the integrated circuits specified herein shall be 0.7 grammes for the flat package, 0.6 grammes for the chip carrier package and 2.2 grammes for the dual-in-line package.

### 4.4 MATERIALS AND FINISHES

The materials and finishes shall be as specified herein. Where a definite material is not specified, a material which will enable the integrated circuits specified herein to meet the performance requirements of this specification shall be used. Acceptance or approval of any constituent material does not guarantee acceptance of the finished product.

#### 4.4.1 Case

The case shall be hermetically sealed and have a metal body with hard glass seals or a ceramic body and the lids shall be welded, brazed, preform-soldered or glass frit-sealed.

#### 4.4.2 Lead Material and Finish

For dual-in-line and flat packages, the material shall be either Type 'D' or Type 'G' with either Type '4' or Type '7' finish in accordance with the requirements of ESA/SCC Basic Specification No. 23500. For chip carrier packages, the finish shall be either Type '4' or Type '7' in accordance with the requirements of ESA/SCC Basic Specification No. 23500. (See Table 1(a) for Type Variants).

### 4.5 MARKING

#### 4.5.1 General

The marking of all components delivered to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 21700. Each component shall be marked in respect of:-

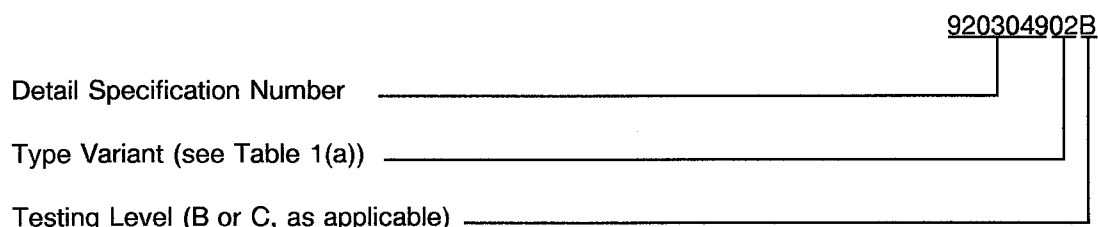
- (a) Lead Identification.
- (b) The SCC Component Number.
- (c) Traceability Information.

#### 4.5.2 Lead Identification

For dual-in-line and flat packages, an index shall be located at the top of the package in the position defined in Note 1 to Figure 2 or, alternatively, a tab may be used to identify Pin No. 1. The pin numbering must be read with the index or tab on the left-hand side. For chip carrier packages, the index shall be as defined by Figure 2(b).

**4.5.3 The SCC Component Number**

Each component shall bear the SCC Component Number which shall be constituted and marked as follows:



**4.5.4 Traceability Information**

Each component shall be marked in respect of traceability information in accordance with the requirements of ESA/SCC Basic Specification No. 21700.

**4.6 ELECTRICAL MEASUREMENTS**

**4.6.1 Electrical Measurements at Room Temperature**

The parameters to be measured in respect of electrical characteristics are scheduled in Table 2. Unless otherwise specified, the measurements shall be performed at  $T_{amb} = +22 \pm 3$  °C.

**4.6.2 Electrical Measurements at High and Low Temperatures**

The parameters to be measured at high and low temperatures are scheduled in Table 3. The measurements shall be performed at  $T_{amb} = +125(+0-5)$  °C and  $-55(+5-0)$  °C respectively.

**4.6.3 Circuits for Electrical Measurements**

Circuits for use in performing electrical measurements listed in Tables 2 and 3 of this specification are shown in Figure 4.

**4.7 BURN-IN TESTS**

**4.7.1 Parameter Drift Values**

The parameter drift values applicable to burn-in are specified in Table 4 of this specification. Unless otherwise stated, measurements shall be performed at  $T_{amb} = +22 \pm 3$  °C. The parameter drift values ( $\Delta$ ) applicable to the parameters scheduled, shall not be exceeded. In addition to these drift value requirements, the appropriate limit value specified for a given parameter in Table 2 shall not be exceeded.

**4.7.2 Conditions for Power Burn-in**

The requirements for power burn-in are specified in Section 7 of ESA/SCC Generic Specification No. 9000. The conditions for power burn-in shall be as specified in Table 5 of this specification.

**4.7.3 Electrical Circuits for Power Burn-in**

Circuits for use in performing the power burn-in tests are shown in Figure 5 of this specification.



**TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - d.c. PARAMETERS**

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST D/F = DIP AND FP C = CCP)	LIMITS		UNIT
						MIN	MAX	
1	Functional Test	-	-	3(b)	Verify Truth Table with Load. Note 1	-	-	-
2 to 7	Input Current High Level at Clock, J or $\bar{K}$	$I_{IH1}$	3010	4(a)	$V_{CC} = 5.5V$ , $V_{IN} = 2.7V$ (Pins D/F 2-3-4-12-13-14) (Pins C 3-4-5-15-17-18)	-	20	$\mu A$
8 to 13	Input Current High Level at Clock, J or $\bar{K}$ (Max. Input Voltage)	$I_{IH2}$	3010	4(a)	$V_{CC} = 5.5V$ , $V_{IN} = 7.0V$ (Pins D/F 2-3-4-12-13-14) (Pins C 3-4-5-15-17-18)	-	100	$\mu A$
14 to 17	Input Current High Level at Clear or Preset	$I_{IH3}$	3010	4(a)	$V_{CC} = 5.5V$ , $V_{IN} = 2.7V$ (Pins D/F 1-5-11-15) (Pins C 2-7-14-19)	-	40	$\mu A$
18 to 21	Input Current High Level at Clear or Preset (Max. Input Voltage)	$I_{IH4}$	3010	4(a)	$V_{CC} = 5.5V$ , $V_{IN} = 7.0V$ (Pins D/F 1-5-11-15) (Pins C 2-7-14-19)	-	200	$\mu A$
22 to 31	Input Clamp Voltage	$V_{IC}$	3008	4(b)	$V_{CC} = 4.5V$ , $I_{IN} = -18mA$ Note 2 (Pins D/F 1-2-3-4-5-11-12-13-14-15) (Pins C 2-3-4-5-7-14-15-17-18-19)	-	-1.5	V
32 to 37	Input Current Low Level at Clock, J or $\bar{K}$	$I_{IL1}$	3009	4(c)	$V_{CC} = 5.5V$ , $V_{IL} = 0.4V$ (Pins D/F 2-3-4-12-13-14) (Pins C 3-4-5-15-17-18)	-	-200	$\mu A$
38 to 41	Input Current Low Level at Clear or Preset	$I_{IL2}$	3009	4(c)	$V_{CC} = 5.5V$ , $V_{IL} = 0.4V$ (Pins D/F 1-5-11-15) (Pins C 2-7-14-19)	-	-400	$\mu A$
42 to 45	Output Voltage Low Level	$V_{OL}$	3007	4(d)	$V_{CC} = 4.5V$ , $V_{IH} = 2.0V$ $V_{IL} = 0.7V$ , $I_{OL} = 4.0mA$ (Pins D/F 6-7-9-10) (Pins C 8-9-12-13)	-	0.4	V
46 to 49	Output Voltage High Level 1	$V_{OH1}$	3006	4(e)	$V_{CC} = 4.5V$ , $V_{IH} = 2.0V$ $V_{IL} = 0.7V$ , $I_{OH} = -400\mu A$ (Pins D/F 6-7-9-10) (Pins C 8-9-12-13)	2.5	-	V

**NOTES:** See Page 20.

**SCC**

ESA/SCC Detail Specification  
 No. 9203/049

PAGE 18

ISSUE 2

**TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - d.c. PARAMETERS (CONT'D)**

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST D/F = DIP AND FP C = CCP)	LIMITS		UNIT
						MIN	MAX	
50 to 53	Output Voltage High Level 2	$V_{OH2}$	3006	4(e)	$V_{CC} = 5.5V$ , $V_{IH} = 2.0V$ $V_{IL} = 0.7V$ , $I_{OH} = -400\mu A$ (Pins D/F 6-7-9-10) (Pins C 8-9-12-13)	3.5	-	V
54 to 57	One Half of the True Output Short Circuit Current	$I_{OS/2}$	3011	4(f)	$V_{CC} = 5.5V$ , $V_{OUT} = 2.25V$ Note 3 Variants 01 to 06 Variants 07 to 12 (Pins D/F 6-7-9-10) (Pins C 8-9-12-13)	-10 -30	-60 -112	mA
58 to 59	Supply Current	$I_{CC}$	3005	4(g)	$V_{CC} = 5.5V$ Note 4 (Pin D/F 16) (Pin C 20)	-	4.0	mA

**NOTES:** See Page 20.

**TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - a.c. PARAMETERS**

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST D/F = DIP AND FP C = CCP) (NOTE 5)	LIMITS		UNIT										
						MIN	MAX											
60 to 67	Propagation Delay Low to High Level from $\overline{\text{Preset}}$ or $\overline{\text{Clear}}$ to Q or $\overline{\text{Q}}$	$t_{\text{PLH1}}$	3003	4(h)	$V_{\text{CC}} = 4.5$ and $5.5\text{V}$ $C_{\text{L}} = 50\text{pF}$ $R_{\text{L}} = 500\Omega$  <table style="margin-left: auto; margin-right: auto;"> <tr> <td style="text-align: center;"><u>Pins D/F</u></td> <td style="text-align: center;"><u>Pins C</u></td> </tr> <tr> <td style="text-align: center;">1 to 6</td> <td style="text-align: center;">2 to 8</td> </tr> <tr> <td style="text-align: center;">5 to 7</td> <td style="text-align: center;">7 to 9</td> </tr> <tr> <td style="text-align: center;">11 to 9</td> <td style="text-align: center;">14 to 12</td> </tr> <tr> <td style="text-align: center;">15 to 10</td> <td style="text-align: center;">19 to 13</td> </tr> </table>	<u>Pins D/F</u>	<u>Pins C</u>	1 to 6	2 to 8	5 to 7	7 to 9	11 to 9	14 to 12	15 to 10	19 to 13	3.0	15	ns
<u>Pins D/F</u>	<u>Pins C</u>																	
1 to 6	2 to 8																	
5 to 7	7 to 9																	
11 to 9	14 to 12																	
15 to 10	19 to 13																	
68 to 75	Propagation Delay High to Low Level from $\overline{\text{Preset}}$ or $\overline{\text{Clear}}$ to Q or $\overline{\text{Q}}$	$t_{\text{PHL1}}$	3003	4(h)	$V_{\text{CC}} = 4.5$ and $5.5\text{V}$ $C_{\text{L}} = 50\text{pF}$ $R_{\text{L}} = 500\Omega$  <table style="margin-left: auto; margin-right: auto;"> <tr> <td style="text-align: center;"><u>Pins D/F</u></td> <td style="text-align: center;"><u>Pins C</u></td> </tr> <tr> <td style="text-align: center;">1 to 7</td> <td style="text-align: center;">2 to 9</td> </tr> <tr> <td style="text-align: center;">5 to 6</td> <td style="text-align: center;">7 to 8</td> </tr> <tr> <td style="text-align: center;">11 to 10</td> <td style="text-align: center;">14 to 13</td> </tr> <tr> <td style="text-align: center;">15 to 9</td> <td style="text-align: center;">19 to 12</td> </tr> </table>	<u>Pins D/F</u>	<u>Pins C</u>	1 to 7	2 to 9	5 to 6	7 to 8	11 to 10	14 to 13	15 to 9	19 to 12	5.0	17	ns
<u>Pins D/F</u>	<u>Pins C</u>																	
1 to 7	2 to 9																	
5 to 6	7 to 8																	
11 to 10	14 to 13																	
15 to 9	19 to 12																	
76 to 83	Propagation Delay Low to High Level from Clock to Q or $\overline{\text{Q}}$	$t_{\text{PLH2}}$	3003	4(h)	$V_{\text{CC}} = 4.5$ and $5.5\text{V}$ $C_{\text{L}} = 50\text{pF}$ $R_{\text{L}} = 500\Omega$  <table style="margin-left: auto; margin-right: auto;"> <tr> <td style="text-align: center;"><u>Pins D/F</u></td> <td style="text-align: center;"><u>Pins C</u></td> </tr> <tr> <td style="text-align: center;">4 to 6</td> <td style="text-align: center;">5 to 8</td> </tr> <tr> <td style="text-align: center;">4 to 7</td> <td style="text-align: center;">5 to 9</td> </tr> <tr> <td style="text-align: center;">12 to 9</td> <td style="text-align: center;">15 to 12</td> </tr> <tr> <td style="text-align: center;">12 to 10</td> <td style="text-align: center;">15 to 13</td> </tr> </table>	<u>Pins D/F</u>	<u>Pins C</u>	4 to 6	5 to 8	4 to 7	5 to 9	12 to 9	15 to 12	12 to 10	15 to 13	5.0	18	ns
<u>Pins D/F</u>	<u>Pins C</u>																	
4 to 6	5 to 8																	
4 to 7	5 to 9																	
12 to 9	15 to 12																	
12 to 10	15 to 13																	
84 to 91	Propagation Delay High to Low Level from Clock to Q or $\overline{\text{Q}}$	$t_{\text{PHL2}}$	3003	4(h)	$V_{\text{CC}} = 4.5$ and $5.5\text{V}$ $C_{\text{L}} = 50\text{pF}$ $R_{\text{L}} = 500\Omega$  <table style="margin-left: auto; margin-right: auto;"> <tr> <td style="text-align: center;"><u>Pins D/F</u></td> <td style="text-align: center;"><u>Pins C</u></td> </tr> <tr> <td style="text-align: center;">4 to 6</td> <td style="text-align: center;">5 to 8</td> </tr> <tr> <td style="text-align: center;">4 to 7</td> <td style="text-align: center;">5 to 9</td> </tr> <tr> <td style="text-align: center;">12 to 9</td> <td style="text-align: center;">15 to 12</td> </tr> <tr> <td style="text-align: center;">12 to 10</td> <td style="text-align: center;">15 to 13</td> </tr> </table>	<u>Pins D/F</u>	<u>Pins C</u>	4 to 6	5 to 8	4 to 7	5 to 9	12 to 9	15 to 12	12 to 10	15 to 13	5.0	20	ns
<u>Pins D/F</u>	<u>Pins C</u>																	
4 to 6	5 to 8																	
4 to 7	5 to 9																	
12 to 9	15 to 12																	
12 to 10	15 to 13																	

**NOTES:** See Page 20.

**SCC**ESA/SCC Detail Specification  
No. 9203/049

PAGE 20

ISSUE 2

**TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - a.c. PARAMETERS (CONT'D)**

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST D/F = DIP AND FP C = CCP)	LIMITS		UNIT
						MIN	MAX	
108 to 111	Maximum Clock Frequency	$f_{max}$	-	4(h)	$V_{CC} = 4.5$ and $5.5V$ $R_L = 500\Omega$ , $C_L = 50pF$ Note 6 (Pins D/F 4-12) (Pins C 5-15)	30	-	MHz

**NOTES**

1. Go-no-go test with  $V_{IL} = 0.3V$ ,  $V_{IH} = 3.0V$ , trip point 1.5V.
2. All inputs and outputs not under test shall be open.
3. No more than 1 output should be tested at a time.
4.  $I_{CC}$  is measured with J,  $\overline{K}$ , Clock and  $\overline{PRE}$  Grounded, then with J,  $\overline{K}$ , Clock and  $\overline{CLR}$  Grounded.
5. Propagation delay measurements shall be performed as a go-no-go test on a 100% basis. Read-and-record measurements shall be performed on an LTPD7 sample basis following the Chart III Burn-in Test.
6. This parameter shall be tested as go-no-go on a 100% basis.

**TABLE 3 - ELECTRICAL MEASUREMENTS AT HIGH AND LOW TEMPERATURES,  
+ 125(+ 0 - 5) °C AND - 55(+ 5 - 0) °C**

NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST D/F = DIP AND FP C = CCP)	LIMITS		UNIT
						MIN	MAX	
1	Functional Test	-	-	3(b)	Verify Truth Table with Load. Note 1	-	-	-
2 to 7	Input Current High Level at Clock, J or $\bar{K}$	$I_{IH1}$	3010	4(a)	$V_{CC} = 5.5V, V_{IN} = 2.7V$ (Pins D/F 2-3-4-12-13-14) (Pins C 3-4-5-15-17-18)	-	20	$\mu A$
8 to 13	Input Current High Level at Clock, J or $\bar{K}$ (Max. Input Voltage)	$I_{IH2}$	3010	4(a)	$V_{CC} = 5.5V, V_{IN} = 7.0V$ (Pins D/F 2-3-4-12-13-14) (Pins C 3-4-5-15-17-18)	-	100	$\mu A$
14 to 17	Input Current High Level at Clear or Preset	$I_{IH3}$	3010	4(a)	$V_{CC} = 5.5V, V_{IN} = 2.7V$ (Pins D/F 1-5-11-15) (Pins C 2-7-14-19)	-	40	$\mu A$
18 to 21	Input Current High Level at Clear or Preset (Max. Input Voltage)	$I_{IH4}$	3010	4(a)	$V_{CC} = 5.5V, V_{IN} = 7.0V$ (Pins D/F 1-5-11-15) (Pins C 2-7-14-19)	-	200	$\mu A$
22 to 31	Input Clamp Voltage	$V_{IC}$	3008	4(b)	$V_{CC} = 4.5V, I_{IN} = -18mA$ Note 2 (Pins D/F 1-2-3-4-5-11-12-13-14-15) (Pins C 2-3-4-5-7-14-15-17-18-19)	-	- 1.5	V
32 to 37	Input Current Low Level at Clock, J or $\bar{K}$	$I_{IL1}$	3009	4(c)	$V_{CC} = 5.5V, V_{IL} = 0.4V$ (Pins D/F 2-3-4-12-13-14) (Pins C 3-4-5-15-17-18)	-	- 200	$\mu A$
38 to 41	Input Current Low Level at Clear or Preset	$I_{IL2}$	3009	4(c)	$V_{CC} = 5.5V, V_{IL} = 0.4V$ (Pins D/F 1-5-11-15) (Pins C 2-7-14-19)	-	- 400	$\mu A$
42 to 45	Output Voltage Low Level	$V_{OL}$	3007	4(d)	$V_{CC} = 4.5V, V_{IH} = 2.0V$ $V_{IL} = 0.7V, I_{OL} = 4.0mA$ (Pins D/F 6-7-9-10) (Pins C 8-9-12-13)	-	0.4	V
46 to 49	Output Voltage High Level 1	$V_{OH1}$	3006	4(e)	$V_{CC} = 4.5V, V_{IH} = 2.0V$ $V_{IL} = 0.7V, I_{OH} = -400\mu A$ (Pins D/F 6-7-9-10) (Pins C 8-9-12-13)	2.5	-	V

**NOTES:** See Page 20.

**SCC**

ESA/SCC Detail Specification  
 No. 9203/049

PAGE 22

ISSUE 2

**TABLE 3 - ELECTRICAL MEASUREMENTS AT HIGH AND LOW TEMPERATURES,  
 + 125(+ 0 - 5) °C AND - 55(+ 5 - 0) °C (CONT'D)**

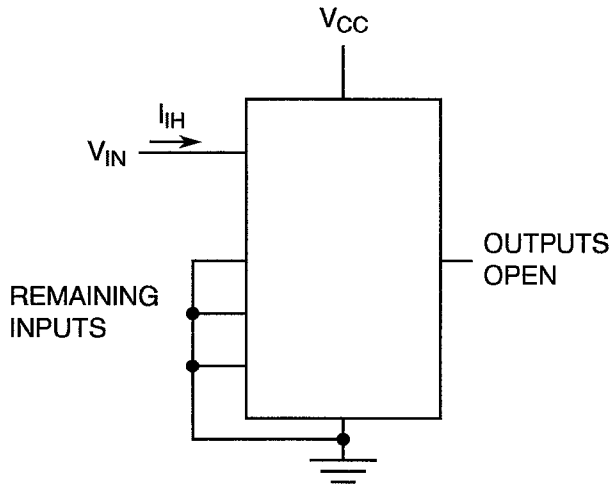
NO.	CHARACTERISTICS	SYMBOL	TEST METHOD MIL-STD 883	TEST FIG.	TEST CONDITIONS (PINS UNDER TEST D/F = DIP AND FP C = CCP)	LIMITS		UNIT
						MIN	MAX	
50 to 53	Output Voltage High Level 2	$V_{OH2}$	3006	4(e)	$V_{CC} = 5.5V$ , $V_{IH} = 2.0V$ $V_{IL} = 0.7V$ , $I_{OH} = -400\mu A$ (Pins D/F 6-7-9-10) (Pins C 8-9-12-13)	3.5	-	V
54 to 57	One Half of the True Output Short Circuit Current	$I_{OS/2}$	3011	4(f)	$V_{CC} = 5.5V$ , $V_{OUT} = 2.25V$ Note 3 Variants 01 to 06 Variants 07 to 12 (Pins D/F 6-7-9-10) (Pins C 8-9-12-13)	-10 -30	-60 -112	mA
58 to 59	Supply Current	$I_{CC}$	3005	4(g)	$V_{CC} = 5.5V$ Note 4 (Pin D/F 16) (Pin C 20)	-	4.0	mA

**NOTES:** See Page 20.



**FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS**

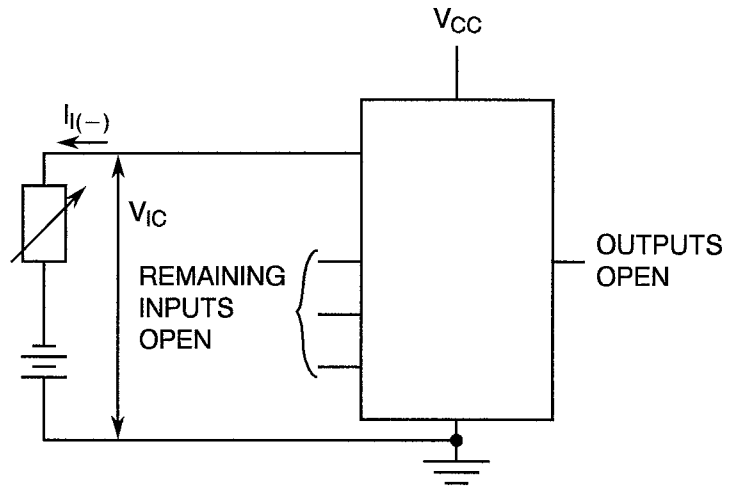
FIGURE 4(a) - INPUT CURRENT HIGH LEVEL



**NOTES**

1. Each input to be tested separately.

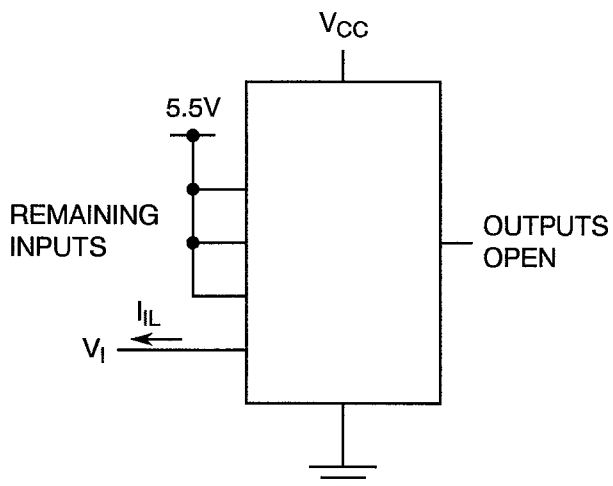
FIGURE 4(b) - INPUT CLAMP VOLTAGE



**NOTES**

1. Each input to be tested separately.

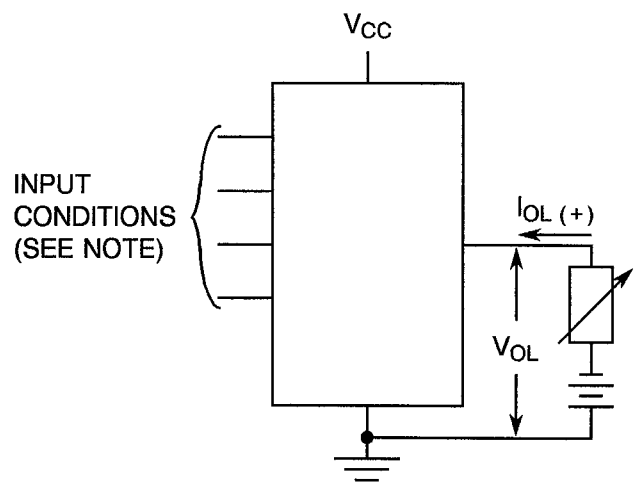
FIGURE 4(c) - LOW LEVEL INPUT CURRENT



**NOTES**

1. Each input to be tested separately.

FIGURE 4(d) - LOW LEVEL OUTPUT VOLTAGE



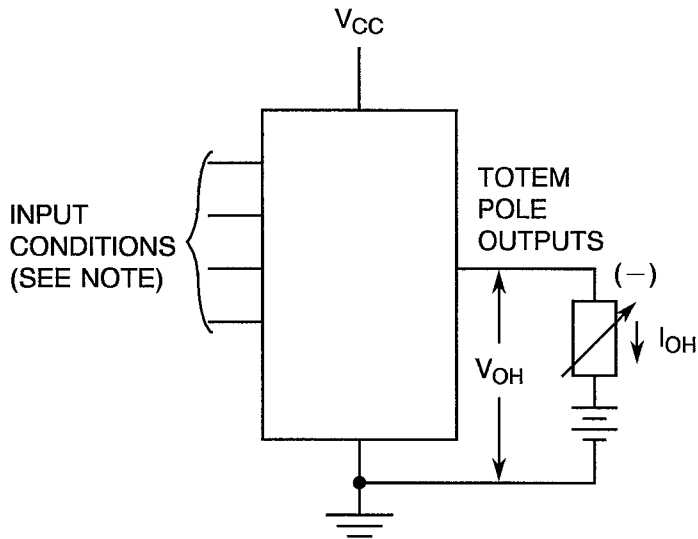
**NOTES**

1. Test per Truth Table



**FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS (CONTINUED)**

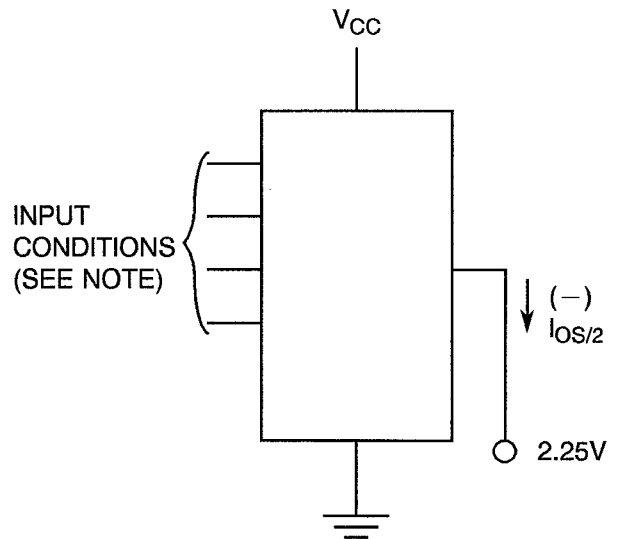
**FIGURE 4(e) - HIGH LEVEL OUTPUT VOLTAGE**



**NOTES**

1. Test per Truth Table.

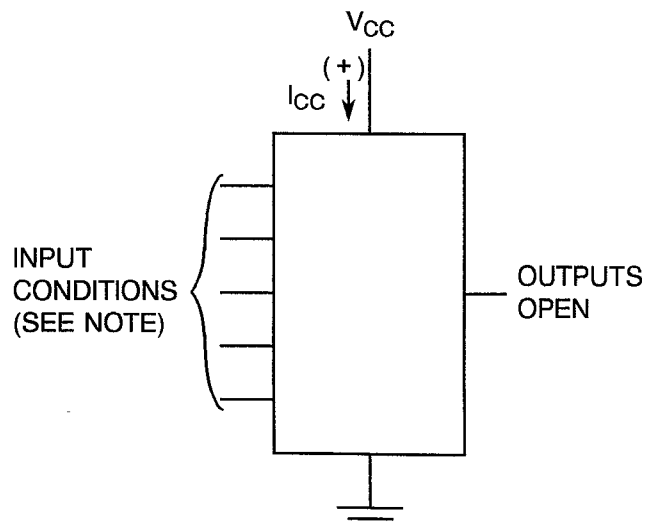
**FIGURE 4(f) - ONE HALF SHORT CIRCUIT OUTPUT CURRENT**



**NOTES**

1. No more than one output should be tested at a time.
2. For  $\bar{Q}$  measurements:  $\overline{\text{Preset}} = 4.5\text{V}$  with all other inputs at ground.  
For Q measurements:  $\overline{\text{Preset}}$ , Clock, J and  $\bar{K} = 0\text{V}$ ,  $\overline{\text{Clear}} = 4.5\text{V}$ .

**FIGURE 4(g) - SUPPLY CURRENT**



**NOTES**

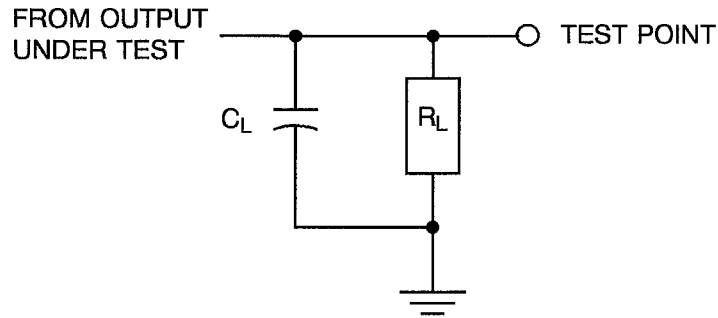
1. See Note 4 on Page 20.



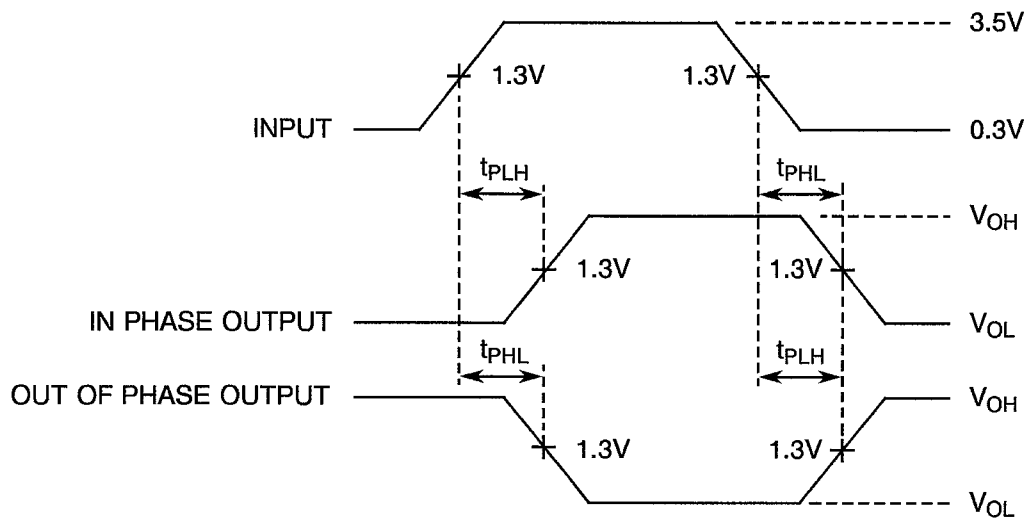


**FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS (CONTINUED)**

FIGURE 4(h) - DYNAMIC TEST AND SWITCHING WAVEFORMS



VOLTAGE WAVEFORMS - PROPAGATION DELAY TIMES



**NOTES**

1. The generator has the following characteristics:  $t_r = t_f = 2\text{ns}$ ,  $\text{PRR} = 1\text{MHz}$ ,  $Z_{\text{out}} = 50\Omega$ , Duty Cycle = 50%.
2.  $C_L = 50\text{pF} \pm 5\%$  including scope probe, wiring and stray capacitance without package in test fixture.
3. Each flip-flop tested separately.
4.  $R_L = 500\Omega \pm 5\%$ .

**TABLE 4 - PARAMETER DRIFT VALUES**

NO.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITIONS	CHANGE LIMITS ( $\Delta$ )	UNIT
2 to 7	Input Current High Level at Clock, J or K	$I_{IH1}$	As per Table 2	As per Table 2	$\pm 20$ or (1) $\pm 0.5$	% $\mu A$
14 to 17	Input Current High Level at Clear or Preset	$I_{IH3}$	As per Table 2	As per Table 2	$\pm 20$ or (1) $\pm 1.0$	% $\mu A$
32 to 37	Input Current Low Level at Clock, J or K	$I_{IL1}$	As per Table 2	As per Table 2	$\pm 10$	$\mu A$
38 to 41	Input Current Low Level at Clear or Preset	$I_{IL2}$	As per Table 2	As per Table 2	$\pm 20$	$\mu A$
43 to 45	Output Voltage Low Level	$V_{OL}$	As per Table 2	As per Table 2	$\pm 60$	mV
46 to 49	Output Voltage High Level 1	$V_{OH1}$	As per Table 2	As per Table 2	$\pm 200$	mV
50 to 53	Output Voltage High Level 2	$V_{OH2}$	As per Table 2	As per Table 2	$\pm 200$	mV

**NOTES**

1. Whichever is greater referred to the initial value.

**TABLE 5 - CONDITIONS FOR POWER BURN-IN AND OPERATING LIFE TEST**

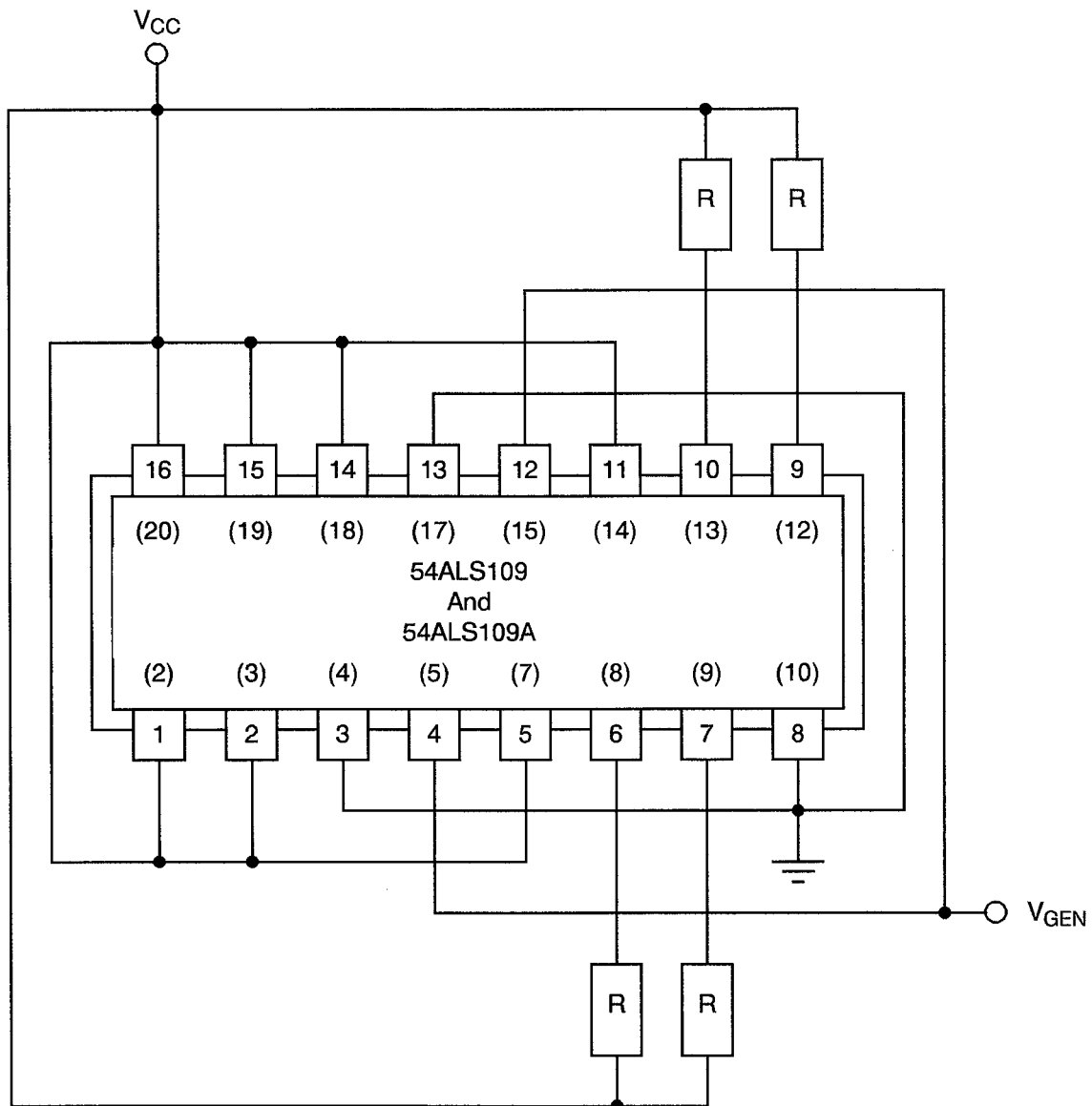
NO.	CHARACTERISTICS	SYMBOL	CONDITION	UNIT
1	Ambient Temperature	$T_{amb}$	+ 125( + 0 – 5)	$^{\circ}C$
2	Power Supply Voltage	$V_{CC}$	+ 5( + 0.5 – 0)	V
3	Pulse Voltage	$V_{GEN}$	0.5 max. to 3.0 min.	Vac
4	Frequency	f	100 (See Note 1)	Hz
5	Fan-out	-	10	-
6	Rise Time	$t_r$	50 max.	$\mu s$
7	Fall Time	$t_f$	50 max.	$\mu s$
8	Duty Cycle	-	20 min.	%

**NOTES**

1. Tolerance  $\pm 10\%$ .



**FIGURE 5 - ELECTRICAL CIRCUIT FOR POWER BURN-IN AND OPERATING LIFE TEST**



**NOTES**

1. Pin numbers in parenthesis are for the chip carrier package.
2.  $R = 1.2k\Omega$ .



#### 4.8 ENVIRONMENTAL AND ENDURANCE TESTS (CHARTS IV AND V OF ESA/SCC GENERIC SPECIFICATION NO. 9000)

##### 4.8.1 Electrical Measurements on Completion of Environmental Tests

The parameters to be measured on completion of environmental tests are scheduled in Table 6. Unless otherwise stated, the measurements shall be performed at  $T_{amb} = +22 \pm 3$  °C.

##### 4.8.2 Electrical Measurements at Intermediate Points during Endurance Tests

The parameters to be measured at intermediate points during endurance tests are as scheduled in Table 6 of this specification. Unless otherwise stated, the measurements shall be performed at  $T_{amb} = +22 \pm 3$  °C.

##### 4.8.3 Electrical Measurements on Completion of Endurance Tests

The parameters to be measured on completion of endurance testing are as scheduled in Table 6 of this specification. Unless otherwise stated, the measurements shall be performed at  $T_{amb} = +22 \pm 3$  °C.

##### 4.8.4 Conditions for Operating Life Tests

The requirements for operating life testing are specified in Section 9 of ESA/SCC Generic Specification No. 9000. The conditions for operating life testing shall be as specified in Table 5 of this specification.

##### 4.8.5 Electrical Circuits for Operating Life Tests

Circuits for use in performing the operating life tests are shown in Figure 5.

##### 4.8.6 Conditions for High Temperature Storage Test

The requirements for the high temperature storage test are specified in ESA/SCC Generic Specification No. 9000. The conditions for high temperature storage shall be  $T_{amb} = +150(+0-5)$  °C.

**TABLE 6 - ELECTRICAL MEASUREMENTS ON COMPLETION OF ENVIRONMENTAL TESTS AND AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTS**

NO.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITIONS	CHANGE LIMITS		UNIT
					( $\Delta$ )	ABSOLUTE	
2 to 7	Input Current High Level at Clock, J or $\bar{K}$	$I_{IH1}$	As per Table 2	As per Table 2	$\pm 1$	-	$\mu A$
8 to 13	Input Current High Level at Clock, J or $\bar{K}$ (Max. Input Voltage)	$I_{IH2}$	As per Table 2	As per Table 2	-	100	$\mu A$
14 to 17	Input Current High Level at Clear or Preset	$I_{IH3}$	As per Table 2	As per Table 2	$\pm 2$	-	$\mu A$
18 to 21	Input Current High Level at Clear or Preset (Max. Input Voltage)	$I_{IH4}$	As per Table 2	As per Table 2	-	200	$\mu A$
32 to 37	Input Current Low Level at Clock, J or $\bar{K}$	$I_{IL1}$	As per Table 2	As per Table 2	$\pm 10$	-	$\mu A$
38 to 41	Input Current Low Level at Clear or Preset	$I_{IL2}$	As per Table 2	As per Table 2	$\pm 20$	-	$\mu A$
42 to 45	Output Voltage Low Level	$V_{OL}$	As per Table 2	As per Table 2	$\pm 60$	-	mV
46 to 49	Output Voltage High Level 1	$V_{OH1}$	As per Table 2	As per Table 2	$\pm 200$	-	mV
50 to 53	Output Voltage High Level 2	$V_{OH2}$	As per Table 2	As per Table 2	$\pm 200$	-	mV
58 to 59	Supply Current	$I_{CC}$	As per Table 2	As per Table 2	$\pm 20$	-	%



**APPENDIX 'A'**

**AGREED DEVIATIONS FOR TEXAS INSTRUMENTS (F)**

ITEMS AFFECTED	DESCRIPTION OF DEVIATIONS
Para. 4.2.1	Scanning Electron Microscope (SEM) Inspection may be performed using TIF document TIF 3.61.610.001.
Para. 4.2.2	Prior to Die Shear Test TIF may perform a Radiographic Inspection on the randomly chosen samples to be subjected to this test, using TIF document TI 50.42-3002.
Para. 4.2.3	Radiographic Inspection may be performed using TIF document TI 50.42-3002.